



<b>Customer</b>	<b>WTL</b>
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# **SPECIFICATION**

**深圳维拓精电科技有限公司**

**WTL International Limited**

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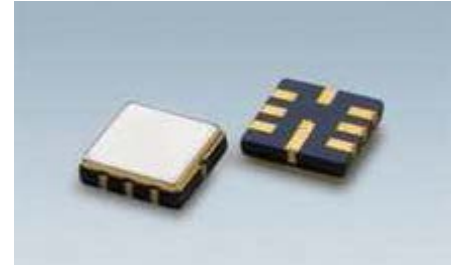
**[www.wtlcrystals.com](http://www.wtlcrystals.com) email: [wtl@wtlcrystals.com](mailto:wtl@wtlcrystals.com)**

# P/N: WTL6A12893

## SAW RESONATOR

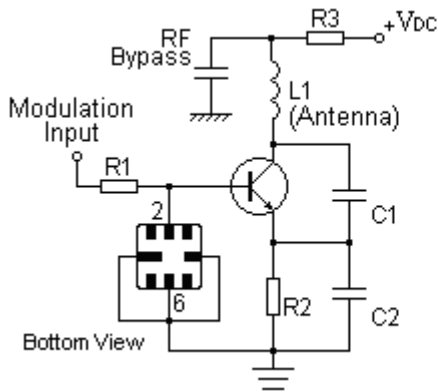


- 1-port Resonator
- Ceramic Package for **Surface Mounted Technology (SMT)**
- **RoHS** compatible
- Package size 5.00x5.00x1.50mm<sup>3</sup>
- Package Code QCC8C
- **Electrostatic Sensitive Device(ESD)**

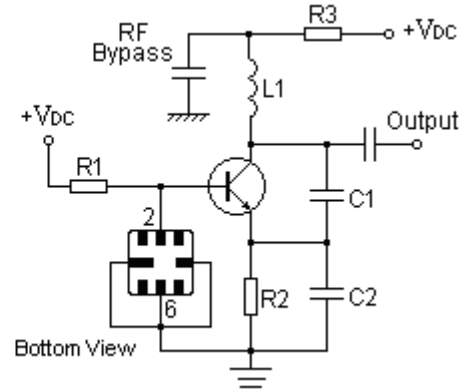


### Application

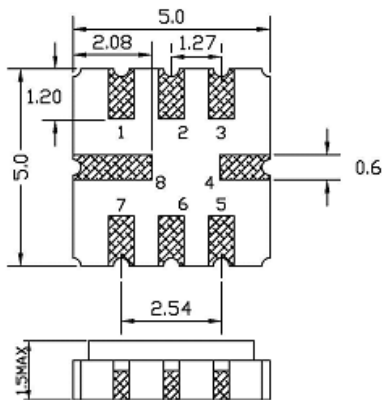
Typical Low-Power Transmitter Application



Typical Local Oscillator Application

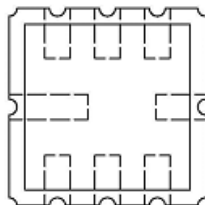


### Package Dimensions (QCC8C)

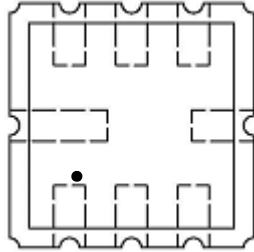


### Pin Configuration

<b>2</b>	Input
<b>6</b>	Output
<b>1,3,4,5,7,8</b>	Ground

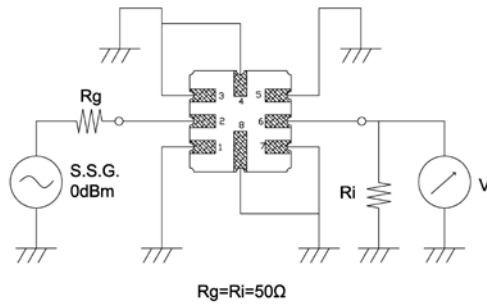


**Marking**

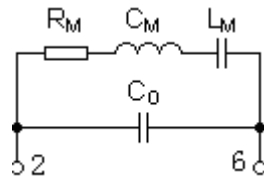


<b>SF</b>	Trademark
<b>R</b>	SAW Resonator
<b>433D</b>	Part number

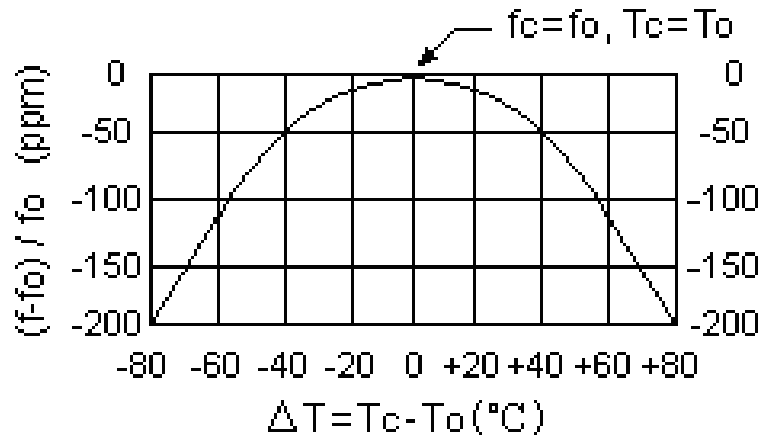
**Test Circuit**



**Equivalent LC Model**



**Temperature Characteristics**



The curve shown above accounts for resonator contribution only and does not include LC component temperature contributions.

**Performance**

**Maximum Rating**

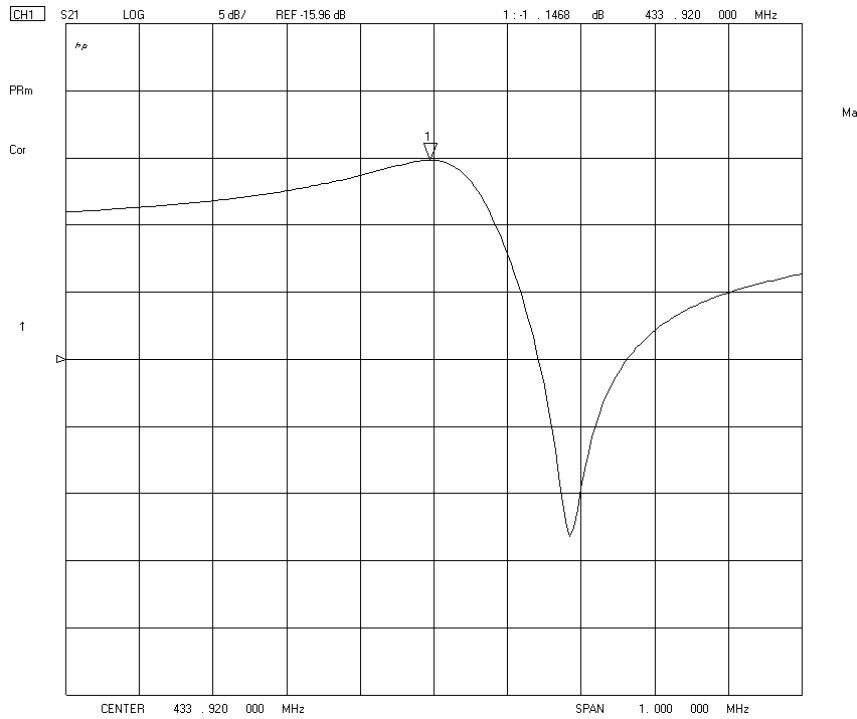
Item		Value	Unit
DC Voltage	$V_{DC}$	$\pm 30$	V
Operation Temperature	T	-40 ~ +120	°C
Storage Temperature	$T_{stg}$	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

**Electronic Characteristics**

Test Temperature:  $25^{\circ}\text{C} \pm 2^{\circ}\text{C}$   
 Terminating source impedance:  $50\Omega$   
 Terminating load impedance:  $50\Omega$

Item			Minimum	Typical	Maximum	Unit
Center Frequency	Absolute Frequency	$f_c$		433.92		MHz
	Tolerance from 433.92MHz	$\Delta f_c$		$\pm 75$		KHz
Insertion Loss(min)		IL		1.2	1.7	dB
Quality Factor	Unloaded Q	$Q_U$		16090		
	$50\Omega$ Loaded Q	$Q_L$		1800		
Temperature Stability	Turnover Temperature	$T_0$	25	40	55	°C
	Turnover Frequency	$f_0$		$f_c$		
	Frequency Temperature Coefficient	FTC		0.032		ppm/°C
Frequency Aging	Absolute Value during the First Year	$ f_A $		$\leq 10$		ppm/yr
DC Insulation Resistance between Any Two Pins			1.0			$M\Omega$
RF Equivalent RLC Model	Motional Resistance	$R_M$		13.0	22.0	$\Omega$
	Motional Inductance	$L_M$		74.4		$\mu\text{H}$
	Motional Capacitance	$C_M$		1.81		fF
	Static Capacitance	$C_0$	2.3	2.6	2.9	pF

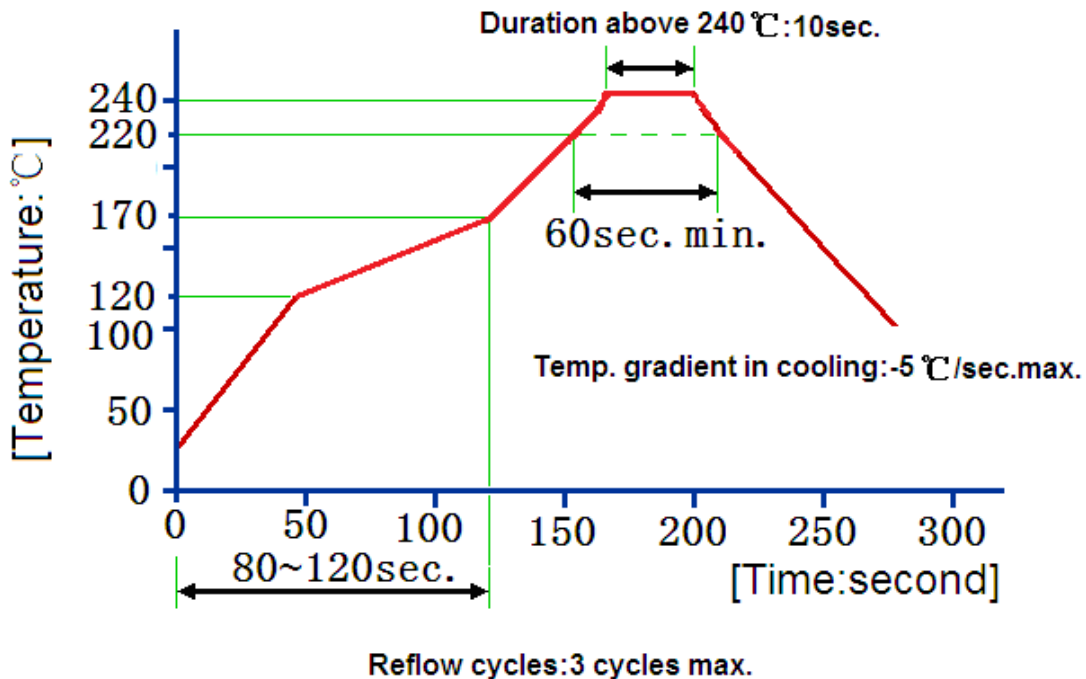
**Frequency Response**



**Reliability (The SAW components shall remain electrical performance after tests)**

No.	Test item	Test condition
1	Temperature Storage	(1) Temperature: 85 °C ± 2 °C , Duration: 2h ± 0.5h (2) Temperature: -55 °C ± 5 °C , Duration: 250h , Recovery time: 2h ± 0.5h
2	Humidity Test	Conditions: 60 °C ± 2 °C , 90 ~ 95% RH
3	Thermal Shock	Heat cycle conditions: TA = -40 °C ≤ 3min , Cycle time: 100 times , Recovery time : 2h ± 0.5h.
4	Vibration Fatigue	Frequency of vibration: 10~55Hz      Amplitude: 1.5mm Directions: X, Y and Z                      Duration: 2h
5	Drop Test	Cycle time: 10 times                      Height: 1.0m
6	Solder Ability Test	Temperature: 245 °C ± 5 °C                      Duration: 3.0s Depth: DIP--2/3 , SMD--1/5
7	Resistance to Soldering Heat	(1) Thickness of PCB: 1mm , Solder condition: 260 °C ± 5 °C , 1.0s (2) Temperature of Soldering Iron: 350 °C ± 10 °C , Duration: 2h ± 0.5h Recovery time : 2 ± 0.5h

### Recommended Reflow Soldering Diagram



### Notes

1. As a result of the particularity of inner structure of SAW products, it is easy to be broken down by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.